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捷多邦,专业PCB打样工厂,24小时加急出货 TLV571 2.7 V TO 5.5 V,1-CHANNEL,8-BIT, PARALLEL ANALOG-TO-DIGITAL CONVERTER SLAS239A – SEPTEMBER 1999 – REVISED FEBRUARY 2000

features

- Fast Throughput Rate: 1.25 MSPS at 5 V, 625 KSPS at 3 V
- Wide Analog Input: 0 V to AV_{DD}
- Differential Nonlinearity Error: < ± 0.5 LSB
- Integral Nonlinearity Error: < ± 0.5 LSB
- Single 2.7-V to 5.5-V Supply Operation
- Low Power: 12 mW at 3 V and 35 mW at 5 V
- Auto Power Down of 1 mA Max S
- Software Power Down: 10 μA Max
- Internal OSC
- Hardware Configurable
- DSP and Microcontroller Compatible Parallel Interface
- Binary/Twos Complement Output
- Hardware Controlled Extended Sampling
- Hardware or Software Start of Conversion

description

The TLV571 is an 8-bit data acquisition system that combines a high-speed 8-bit ADC and a

parallel interface. The device contains two on-chip control registers allowing control of software conversion start and power down via the bidirectional parallel port. The control registers can be set to a default mode using a dummy RD while WR is tied low allowing the registers to be hardware configurable.

The TLV571 operates from a single 2.7-V to 5.5-V power supply. It accepts an analog input range from 0 V to AV_{DD} and digitizes the input at a maximum 1.25 MSPS throughput rate at 5 V. The power dissipations are only 12 mW with a 3-V supply or 35 mW with a 5-V supply. The device features an auto power-down mode that automatically powers down to 1 mA 50 ns after conversion is performed. In software power-down mode, the ADC is further powered down to only 10 μ A.

Very high throughput rate, simple parallel interface, and low power consumption make the TLV571 an ideal choice for high-speed digital signal processing.

AVAILABLE OPTIONS							
	PACKAGE						
TA	24 TSSOP (PW)	24 SOIC (DW)					
-40°C to 85°C	TLV571IPW	TLV571IDW					
=40 C 10 85 C	TEV57 TIF VV						

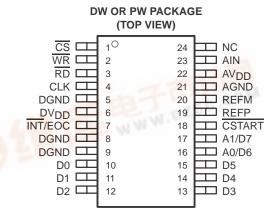


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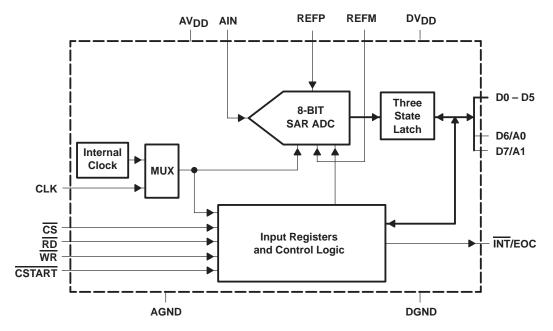
applications

- Mass Storage and HDD
- Automotive
- Digital Servos
- Process Control
- General-Purpose DSP
- Image Sensor Processing



NC - No internal connection

functional block diagram



Terminal Functions

TERMINAL		1/0	DESCRIPTION
NAME	NO.	1 "0	DESCRIPTION
AGND	21		Analog ground
AIN	23	1	ADC analog input
AV _{DD}	22		Analog supply voltage, 2.7 V to 5.5 V
A0/D6	16	I/O	Bidirectional 3-state data bus. D6/A0 along with D7/A1 is used as address lines to access CR0 and CR1 for initialization.
A1/D7	17	I/O	Bidirectional 3-state data bus. D7/A1 along with D6/A0 is used as address lines to access CR0 and CR1 for initialization.
CLK	4	1	External clock input
CS	1	1	Chip select. A logic low on CS enables the TLV571.
CSTART	18	1	Hardware sample and conversion start input. The falling edge of CSTART starts sampling and the rising edge of CSTART starts conversion.
DGND	5, 8, 9		Digital ground
DV _{DD}	6		Digital supply voltage, 2.7 V to 5.5 V
D0 – D5	10–15	I/O	Bidirectional 3-state data bus
INT/EOC	7	0	End-of-conversion/interrupt
NC	24		Not connected
RD	3	1	Read data. A falling edge on \overline{RD} enables a read operation on the data bus when \overline{CS} is low.
REFM	20	1	Lower reference voltage (nominally ground). REFM must be supplied or REFM pin must be grounded.
REFP	19	I	Upper reference voltage (nominally AV _{DD}). The maximum input voltage range is determined by the difference between the voltage applied to REFP and REFM.
WR	2	I	Write data. A rising edge on the \overline{WR} latches in configuration data when \overline{CS} is low. When using software conversion start, a rising edge on \overline{WR} also initiates an internal sampling start pulse. When \overline{WR} is tied to ground, the ADC in nonprogrammable (hardware configuration mode).



detailed description

analog-to-digital SAR converter

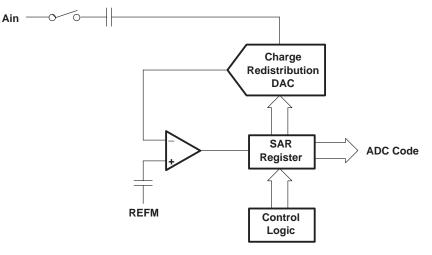


Figure 1

The TLV571 is a successive-approximation ADC utilizing a charge redistribution DAC. Figure 1 shows a simplified version of the ADC.

The sampling capacitor acquires the signal on Ain during the sampling period. When the conversion process starts, the SAR control logic and charge redistribution DAC are used to add and subtract fixed amounts of charge from the sampling capacitor to bring the comparator into a balanced condition. When the comparator is balanced, the conversion is complete and the ADC output code is generated.

sampling frequency, fs

The TLV571 requires 16 CLKs for each conversion, therefore the equivalent maximum sampling frequency achievable with a given CLK frequency is:

 $f_{s(max)} = (1/16) f_{CLK}$

The TLV571 is software configurable. The first two MSB bits, D(7,6) are used to address which register to set. The remaining six bits are used as control data bits. There are two control registers, CR0 and CR1, that are user configurable. All of the register bits are written to the control register during write cycles. A description of the control registers is shown in Figure 2.



detailed description (continued)

control registers

A1 A0	D5	D4	D3	D2	D1	D0					
Control Register Zero (CR0)											
A(1:0)=00	D5	D4	D3	D2	D1	D0					
A(1.0)=00	STARTSEL	PROGEOC	CLKSEL	SWPWDN	Don't Care	Don't Care					
	0: HARDWARE START (CSTART) 1:	0: INT 1: EOC	0: Internal Clock 1:	0: NORMAL 1: Powerdown	Don't Care	Don't Care					
	SOFTWARE START		External Clock								

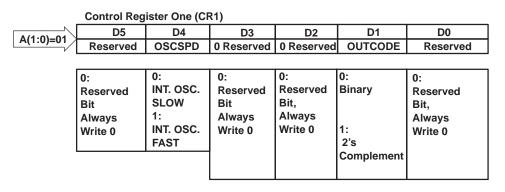


Figure 2. Input Data Format

hardware configuration option

The TLV571 can configure itself. This option is enabled when the \overline{WR} pin is tied to ground and a dummy \overline{RD} signal is applied. The ADC is now fully configured. Zeros or default values are applied to both control registers. The ADC is configured ideally for 3-V operation, which means the internal OSC is set at 10 MHz and hardware start of conversion using \overline{CSTART} .

ADC conversion modes

The TLV571 provides two start of conversion modes. Table 1 explains these modes in more detail.



detailed description (continued)

Table 1. Conversion Modes

START OF CONVERSION	OPERATION	COMMENTS – FOR INPUT
Hardware start (CSTART) CR0.D5 = 0	 <u>Repeated</u> conversions from AIN <u>CSTART</u> falling edge to start sampling <u>CSTART</u> rising edge to start conversion If in INT mode, one INT pulse generated after each conversion If in EOC mode, EOC will go high to low at start of conversion, and return high at end of conversion. 	CSTART rising edge must be applied a minimum of 5 ns before or after CLK rising edge.
Software start CR0.D5 = 1	 <u>Rep</u>eated conversions from AIN WR rising edge to start sampling initially. Thereafter, sampling occurs at the rising edge of RD. Conversion begins after 6 clocks after sampling has begun. Thereafter, if in INT mode, one INT pulse generated after each conversion If in EOC mode, EOC will go high to low at start of conversion and return high at end of conversion. 	With external clock, WR and RD rising edge must be a minimum 5 ns before or after CLK rising edge.

configure the device

The device can be configured by writing to control registers CR0 and CR1.

REGISTER	IND	EX	D5	D4	D3	D2	D1	D0	COMMENT
REGISTER	D7	D6	05	D4	03			00	COMMENT
EXAMPLE1									
CR0	0	0	0	0	0	0	0	0	Normal, INT OSC
CR1	0	1	0	0	0	0	0	0	Binary
EXAMPLE2									
CR0	0	0	0	1	1	1	0	0	Power down, EXT OSC
CR1	0	1	0	0	0	0	1	0	2's complement output

power down

The TLV571 offers two power down modes, auto power down and software power down. This device will automatically proceed to auto power down mode if RD is not present one clock after conversion. Software power down is controlled directly by the user by pulling \overline{CS} to DV_{DD} .

Table 3. Power Down Modes

PARAMETERS/MODES	AUTO POWER DOWN	SOFTWARE POWER DOWN (CS = DV _{DD})
Maximum power down dissipation current	1 mA	10 µA
Comparator	Power down	Power down
Clock buffer	Power down	Power down
Control registers	Saved	Saved
Minimum power down time	1 CLK	2 CLK
Minimum resume time	1 CLK	2 CLK



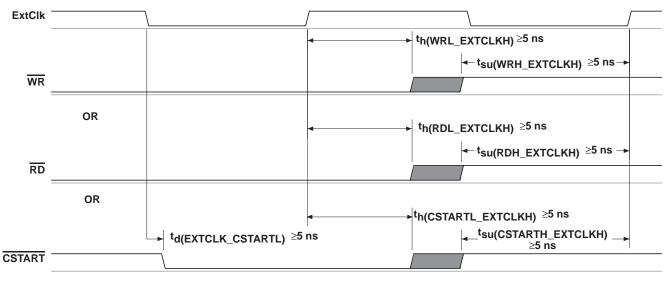
detailed description (continued)

reference voltage input

The TLV571 has two reference input pins: REFP and REFM. The voltage levels applied to these pins establish the upper and lower limits of the analog inputs to produce a full-scale and zero-scale reading respectively. The values of REFP, REFM, and the analog input should not exceed the positive supply or be less than GND consistent with the specified absolute maximum ratings. The digital output is at full scale when the input signal is equal to or higher than REFP and is at zero when the input signal is equal to or lower than REFM.

sampling/conversion

All sampling, conversion, and data output in the device are started by a trigger. This could be the RD, WR, or CSTART signal depending on the mode of conversion and configuration. The rising edge of RD, WR, and CSTART signal are extremely important, since they are used to start the conversion. These edges need to stay close to the rising edge of the external clock (if it is used as CLK). The minimum setup and hold time with respect to the rising edge of the external clock should be 5 ns minimum. When the internal clock is used, this is not an issue since these two edges will start the internal clock automatically. Therefore, the setup time is always met. Software controlled sampling lasts 6 clock cycles. This is done via the CLK input or the internal oscillator if enabled. The input clock frequency can be 1 MHz to 20 MHz, translating into a sampling time from 0.6 µs to 0.3 µs. The internal oscillator frequency is 9 MHz minimum (ocillator frequency is between 9 MHz to 22 MHz), translating into a sampling time from 0.6 μ s to 0.3 μ s. Conversion begins immediately after sampling and lasts 10 clock cycles. This is again done using the external clock input (1 MHz-20 MHz) or the internal oscillator (9 MHz minimum) if enabled. Hardware controlled sampling, via CSTART, begins on falling CSTART lasts the length of the active CSTART signal. This allows more control over the sampling time, which is useful when sampling sources with large output impedances. On rising CSTART, conversion begins. Conversion in hardware controlled mode also lasts 10 clock cycles. This is done using the external clock input (1 MHz-20 MHz) or the internal oscillator (9 MHz minimum) as is the case in software controlled mode.



NOTE: t_{SU} = setup time, t_h = hold time





start of conversion mechanism

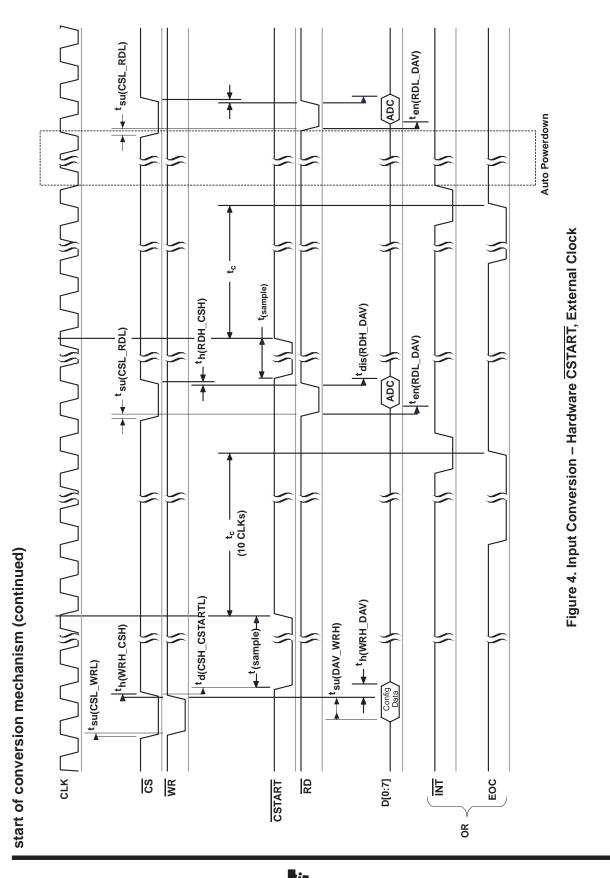
There are two ways to convert data: hardware and software. In the hardware conversion mode the ADC begins sampling at the falling edge of CSTART and begins conversion at the rising edge of CSTART. Software start mode ADC samples for 6 clocks, then conversion occurs for ten clocks. The total sampling and conversion process lasts only 16 clocks in this case. If RD is not detected during the next clock cycle, the ADC automatically proceeds to a power-down state. Data is valid on the rising edge of INT in both conversion modes.

hardware CSTART conversion

external clock

With \overline{CS} low and \overline{WR} low, data is written into the ADC. The sampling begins at the falling edge of \overline{CSTART} and conversion begins at the rising edge of \overline{CSTART} . At the end of conversion, EOC goes from low to high, telling the host that conversion is ready to be read out. The external clock is active and is used as the reference at all times. With this mode, it is required that \overline{CSTART} is not applied at the rising edge of the clock (see Figure 4).

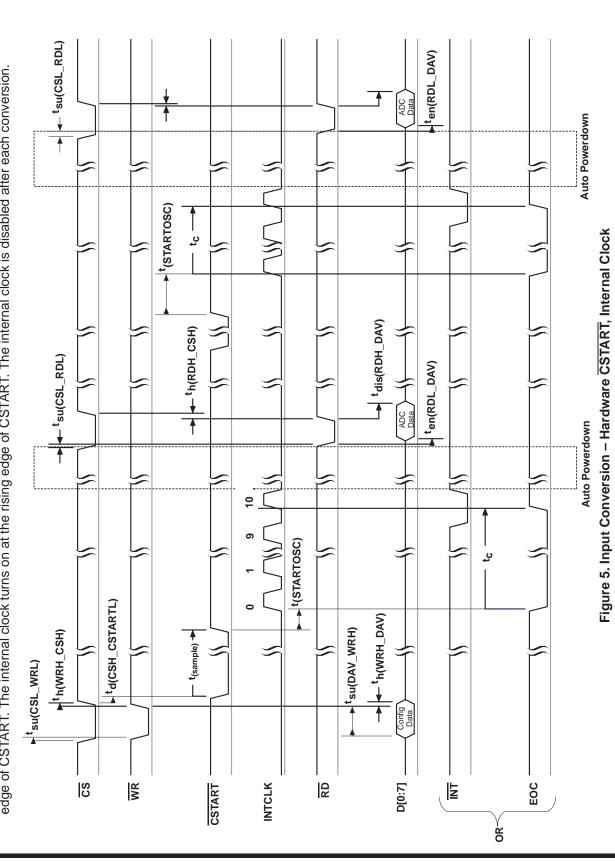




TEXAS

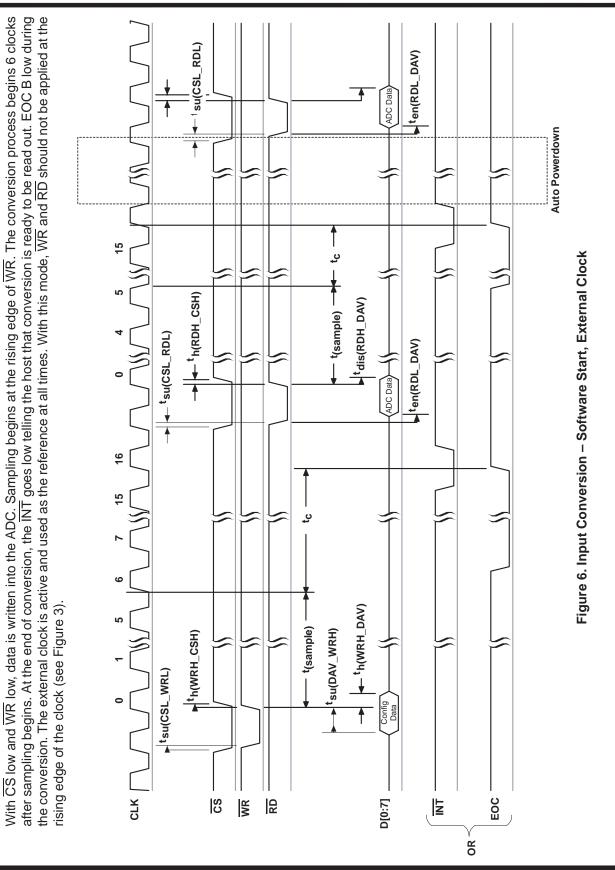


With CS low and WR low, data is written into the ADC. The sampling begins at the falling edge of CSTART, and conversion begins at the rising edge of CSTART. The internal clock is disabled after each conversion.



TEXAS

TLV571 2.7 V TO 5.5 V, 1-CHANNEL, 8-BIT PARALLEL ANALOG-TO-DIGITAL CONVERTER SLAS239A - SEPTEMBER 1999 - REVISED FEBRUARY 2000



TEXAS

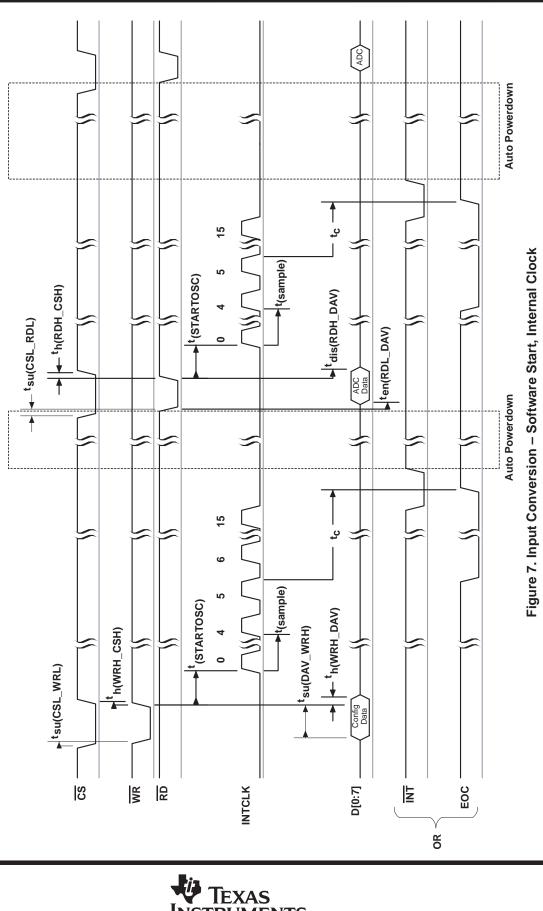
software START conversion

external clock

software START conversion (continued)

internal clock

With <u>CS</u> low and <u>WR</u> low, data is written into the ADC. Sampling begins at the rising edge of <u>WR</u>. Conversion begins 6 clocks after sampling begins. The internal clock begins at the rising edge of <u>WR</u>. The internal clock is disabled after each conversion. Subsequent sampling begins at the rising edge of <u>RD</u>.



TLV571 2.7 V TO 5.5 V, 1-CHANNEL, 8-BIT PARALLEL ANALOG-TO-DIGITAL CONVERTER SLAS239A – SEPTEMBER 1999 – REVISED FEBRUARY 2000

software START conversion (continued)

system clock source

The TLV571 internally derives multiple clocks from the SYSCLK for different tasks. SYSCLK is used for most conversion subtasks. The source of SYSCLK is programmable via control register zero, bit 3. The source of SYSCLK is changed at the rising edge of WR of the cycle when CR0.D3 is programmed.

internal clock (CR0.D3 = 0, SYSCLK = internal OSC)

The TLV571 has a built-in 10 MHz OSC. When the internal OSC is selected as the source of SYSCLK, the internal clock starts with a delay (one half of the OSC period max) after the falling edge of the conversion trigger (either \overline{WR} , \overline{RD} , or \overline{CSTART}). The OSC speed can be set to 10 ± 1 MHz or 20 ± 2 MHz by setting register bit CR1.D4.

external clock (CR0.D3 = 1, SYSCLK = external clock)

The TLV571 is designed to accept an external clock input (CMOS/TTL logic) with frequencies from 1 MHz to 20 MHz.

host processor interface

The TLV571 provides a generic high-speed parallel interface that is compatible with high-performance DSPs and general-purpose microprocessors. The interface includes D(0-7), \overline{INT}/EOC , \overline{RD} , and \overline{WR} .

output format

The data output format is unipolar (code 0 to 255). The output code format can be either binary or twos complement by setting register bit CR1.D1.

power up and initialization

After power up, \overline{CS} must be low to begin an I/O cycle. \overline{INT}/EOC is initially high. The TLV571 requires two write cycles to configure the two control registers. The first conversion after the device has returned from the power down state may be invalid and should be disregarded.

definitions of specifications and terminology

integral nonlinearity

Integral nonlinearity refers to the deviation of each individual code from a line drawn from zero through full scale. The point used as zero occurs 1/2 LSB before the first code transition. The full-scale point is defined as level 1/2 LSB beyond the last code transition. The deviation is measured from the center of each particular code to the true straight line between these two points.

differential nonlinearity

An ideal ADC exhibits code transitions that are exactly 1 LSB apart. DNL is the deviation from this ideal value. A differential nonlinearity error of less than \pm 1 LSB ensures no missing codes.

zero offset

The major carry transition should occur when the analog input is at zero volts. Zero error is defined as the deviation of the actual transition from that point.

gain error

The first code transition should occur at an analog value 1/2 LSB above negative full scale. The last transition should occur at an analog value 1 1/2 LSB below the nominal full scale. Gain error is the deviation of the actual difference between first and last code transitions and the ideal difference between first and last code transitions.



software START conversion (continued)

signal-to-noise ratio + distortion (SINAD)

Signal-to-noise ratio + disortion is the ratio of the rms value of the measured input signal to the rms sum of all other spectral components below the Nyquist frequency, including harmonics but excluding dc. The value for SINAD is expressed in decibels.

effective number of bits (ENOB)

For a sine wave, SINAD can be expressed in terms of the number of bits. Using the following formula,

N = (SINAD - 1.76)/6.02

it is possible to get a measure of performance expressed as N, the effective number of bits. Thus, the effective number of bits for a device for sine wave inputs at a given input frequency can be calculated directly from its measured SINAD.

total harmonic distortion (THD)

Total harmonic distortion is the ratio of the rms sum of the first six harmonic components to the rms value of the measured input signal and is expressed as a percentage or in decibels.

spurious free dynamic range (SFDR)

Spurious free dynamic range is the difference in dB between the rms amplitude of the input signal and the peak spurious signal.

DSP interface

The TLV571 is a 8-bit single input channel analog-to-digital converter with throughput up to 1.25 MSPS at 5 V and up to 625 KSPS at 3 V. To achieve 1.25 MSPS throughput, the ADC must be clocked at 20 MHz. Likewise to achieve 625 KSPS throughout, the ADC must be clocked at 10 MHz. The TLV571 can be easily interfaced to microcontrollers, ASICs, and DSPs. Figure 8 shows the pin connections to interface the TLV571 to the TMS320C6x DSP.

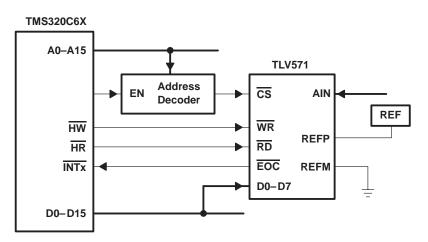


Figure 8. TMS320C6x DSP Interface



grounding and decoupling considerations

General practices should apply to the PCB design to limit high frequency transients and noise that are fed back into the supply and reference lines. This requires that the supply and reference pins be sufficiently bypassed. In most cases $0.1-\mu F$ ceramic chip capacitors are adequate to keep the impedance low over a wide frequency range. Since their effectiveness depends largely on the proximity to the individual supply pin, they should be placed as close to the supply pins as possible.

To reduce high frequency and noise coupling, it is highly recommended that digital and analog grounds be shorted immediately outside the package. This can be accomplished by running a low impedance line between DGND and AGND under the package.

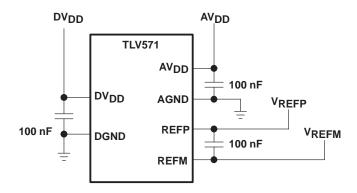
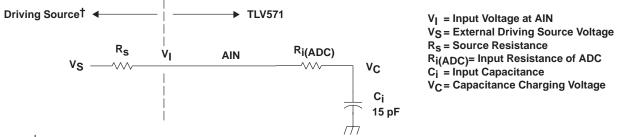


Figure 9. Placement for Decoupling Capacitors

power supply ground layout

Printed-circuit boards that use separate analog and digital ground planes offer the best system performance. Wire-wrap boards do not perform well and should not be used. The two ground planes should be connected together at the low-impedance power-supply source. The best ground connection may be achieved by connecting the ADC AGND terminal to the system analog ground plane making sure that analog ground currents are well managed.



[†] Driving source requirements:

• Noise and distortion for the source must be equivalent to the resolution of the converter.

• R_s must be real at the input frequency.

Figure 10. Equivalent Input Circuit Including the Driving Source



simplified analog input analysis

Using the equivalent circuit in Figure 10, the time required to charge the analog input capacitance from 0 to V_S within 1/2 LSB, t_{ch}(1/2 LSB), can be derived as follows.

The capacitance charging voltage is given by:

$$V_{C(t)} = V_{S} \left(1 - e^{-t} ch^{/R} t^{C} i \right)$$

$$R_{t} = R_{s} + R_{i}$$
(1)

Whe

 $R_i = R_{i(ADC)}$

t_{ch} = Charge time

The input impedance R_i is 718 Ω at 5 V, and is higher (~ 1.25 k Ω) at 2.7 V. The final voltage to 1/2 LSB is given by:

$$V_{\rm C} (1/2 \text{ LSB}) = V_{\rm S} - (V_{\rm S}/512)$$
 (2)

Equating equation 1 to equation 2 and solving for cycle time t_c gives:

$$V_{S} - (V_{S}/512) = V_{S} \left(1 - e^{-t} ch^{/R} t^{C} i \right)$$

a ta change ta 1/2 LSB (minimum compliant time) izi (3)

and time to change to 1/2 LSB (minimum sampling time) is:

 $t_{ch} (1/2 \text{ LSB}) = R_t \times C_i \times \ln(512)$

Where

ln(512) = 6.238

Therefore, with the values given, the time for the analog input signal to settle is:

$$t_{ch}$$
 (1/2 LSB) = (R_s + 718 Ω) × 15 pF × ln(512) (4)

This time must be less than the converter sample time shown in the timing diagrams. Which is 6x SCLK.

$$t_{ch} (1/2 \text{ LSB}) \le 6x \ 1/f_{(SCLK)}$$
(5)

Therefore the maximum SCLK frequency is:

$$Max(f_{(SCLK)}) = 6/t_{ch} (1/2 LSB) = 6/(ln(512) \times R_t \times C_i)$$
(6)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, GND to V _{CC}	−0.3 V to 6.5 V
Analog input voltage range	0.3 V to AV _{DD} + 0.3 V
Reference input voltage range	AV _{DD} + 0.3 V
Digital input voltage range	0.3 V to DV _{DD} + 0.3 V
Operating virtual junction temperature range, T _J	–40°C to 150°C
Operating free-air temperature range, T _A ,	–40°C to 85°C
Storage temperature range, T _{stg}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

power supplies

	MIN	MAX	UNIT
Analog supply voltage, AV _{DD}	2.7	5.5	V
Digital supply voltage, DV _{DD}	2.7	5.5	V

NOTE 1: Abs $(AV_{DD} - DV_{DD}) < 0.5 V$

analog inputs

	MIN	MAX	UNIT
Analog input voltage, AIN	AGND	VREFP	V

digital inputs

		MIN	NOM	MAX	UNIT
High-level input voltage, V _{IH}	$DV_{DD} = 2.7 \text{ V to } 5.5 \text{ V}$	2.1	2.4		V
Low level input voltage, VIL	$DV_{DD} = 2.7 V \text{ to } 5.5 V$			0.8	V
Input CLK frequency	$DV_{DD} = 4.5 \text{ V} \text{ to } 5.5 \text{ V}$			20	MHz
Input CLK frequency	$DV_{DD} = 2.7 \text{ V to } 3.3 \text{ V}$			10	MHz
Pulse duration, CLK high, tw(CLKH)	DV_{DD} = 4.5 V to 5.5 V, f _{CLK} = 20 MHz	23			ns
	DV_{DD} = 2.7 V to 3.3 V, f _{CLK} = 10 MHz	46			ns
Pulse duration, CLK low, tw(CLKL)	DV_{DD} = 4.5 V to 5.5 V, f _{CLK} = 20 MHz	23			ns
Puise duration, CER low, W(CERE)	DV_{DD} = 2.7 V to 3.3 V, f _{CLK} = 10 MHz	46			ns
Rise time, I/O and control, CLK, CS	50 pF output load	4			
Fall time, I/O and control, CLK, CS	50 pF output load	4			ns

reference specifications

	MIN	NOM MAX	UNIT		
	VREFP	$AV_{DD} = 3 V$	2	AV _{DD}	V
	VREFF	$AV_{DD} = 5 V$	2.5	AV _{DD}	V
External reference voltage	VREFM	$AV_{DD} = 3 V$	AGND	1	V
	VREFINI	$AV_{DD} = 5 V$	AGND	2	V
	VREFP – VREFM		2	AV _{DD} –AGND	V



electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted)

digital specifications

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Logic inputs						
IIН	High-level input current	$DV_{DD} = 5 V, DV_{DD} = 3 V, Input = DV_{DD}$	-1		1	μA
١ _{IL}	Low-level input current	$DV_{DD} = 5 V, DV_{DD} = 3 V, Input = 0 V$	-1		1	μA
Ci	Input capacitance			10	15	pF
Logic	outputs					
VOH	High-level output voltage	$I_{OH} = 50 \ \mu A$ to 0.5 mA	DV _{DD} -0.4			V
VOL	Low-level output voltage	$I_{OL} = 50 \ \mu A$ to 0.5 mA			0.4	V
IOZ	High-impedance-state output current	$DV_{DD} = 5 V, DV_{DD} = 3 V, Input = DV_{DD}$			1	μΑ
IOL	Low-impedance-state output current	$DV_{DD} = 5 V, DV_{DD} = 3 V, Input = 0 V$			-1	μA
Co	Output capacitance			5		pF
	Internal clock	3 V, AV _{DD} = DV _{DD}	9	10	11	MHz
	Internal Clock	5 V, AV _{DD} = DV _{DD}	18	20	22	IVIITZ

dc specifications

	PARAMETER		TEST C	ONDITIONS	MIN	TYP	MAX	UNIT
	Resolution					8		Bits
Accu	racy							
	Integral nonlinearity, INL		Best fit			±0.3	±0.5	LSB
	Differential nonlinearity, DNL					±0.3	±0.5	LSB
	Missing codes						0	
EO	Offset error					±0.15%	±0.3%	FSR
EG	Gain error				±0.2%	±0.4%	FSR	
Analo	og input							
Ci			AIN, $AV_{DD} = 3 V$		15		pF	
	Input capacitance	MUX input, AVD		25		pF		
l _{lkg}	Input leakage current	$V_{AIN} = 0$ to AV_D			±1	μΑ		
Volta	ge reference input							
r _i	Input resistance			2			kΩ	
Ci	Input capacitance				300		pF	
Powe	r supply							
	Operating supply current, IDD + IREF		$AV_{DD} = DV_{DD} = 3 V$, f _{CLK} = 10 MHz			4	5.5	mA
			$AV_{DD} = DV_{DD} = 5 V$, $f_{CLK} = 20 MHz$			7	8.5	mA
PD	Power dissipation		$AV_{DD}+DV_{DD} = 3 V$			12	17	mW
FD			$AV_{DD}+DV_{DD} =$		35	43	mW	
		Software		AV _{DD} = 3 V		1	8	μΑ
	Supply autrent in power down mode	Suitwale	^I DD + ^I REF	$AV_{DD} = 5 V$		2	10	μΑ
IPD	Supply current in power-down mode	Auto	IDD + IREF	AV _{DD} = 3 V		0.5	1	mA
				$AV_{DD} = 5 V$		0.5	1	mA



electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted) (continued)

PARAMETER			TEST CONDITIONS			MAX	UNIT
Circulto noise retia CND			f _s = 1.25 MSPS, AV _{DD} = 5 V	47	49		dB
Signal-to-noise ratio, SNR		f _I = 100 kHz, 80% of FS	f _S = 625 KSPS, AV _{DD} = 3 V	47	49		dB
Cignal to paigo ratio y diato	tion CINAD	fl = 100 kHz, 80% of FS	f _S = 1.25 MSPS, AV _{DD} = 5 V	47	49		dB
Signal-to-noise ratio + disto	riion, Sinad		$f_S = 625 \text{ KSPS}, \text{ AV}_{DD} = 3 \text{ V}$	47	49		dB
Total harmonic distortion, T	חח	fj = 100 kHz,	$f_{S} = 1.25 \text{ MSPS}, \text{AV}_{DD} = 5 \text{ V}$		-64	-52	dB
	טח	80% of FS	$f_S = 625 \text{ KSPS}, \text{ AV}_{DD} = 3 \text{ V}$		-62	-52	dB
Effective number of bits, EN		OB f _I = 100 kHz, 80% of FS	$f_S = 1.25 \text{ MSPS}, \text{AV}_{DD} = 5 \text{ V}$	7.5	7.9		Bits
Effective number of bits, En	ЮВ		$f_S = 625 \text{ KSPS}, \text{ AV}_{DD} = 3 \text{ V}$	7.5	7.9		Bits
Sourious free dynamic roos		f _I = 100 kHz, 80% of FS	$f_{S} = 1.25 \text{ MSPS}, \text{AV}_{DD} = 5 \text{ V}$		-65	-51	dB
Spurious free dynamic rang	e, sfdr		$f_S = 625 \text{ KSPS}, \text{ AV}_{DD} = 3 \text{ V}$		-64	-51	dB
nalog input							
Full power bandwidth	-1 dB	Full-scale 0 dE	input sine wave	12	18		MHz
Full-power bandwidth	-3 dB	Full-scale 0 dE	Full-scale 0 dB input sine wave		30		MHz
Small signal bandwidth	–1 dB	–20 dB input s	ine wave	15	20		MHz
Small-signal bandwidth	–3 dB	–20 dB input s	ine wave		35		MHz
Compling rate f	•	AV _{DD} = 4.5 V to 5.5 V		0.0625		1.25	MSP
Sampling rate, f _S		AV _{DD} = 2.7 V to 3.3 V		0.0625		0.625	MSP

ac specifications, $AV_{DD} = DV_{DD} = 5 V$ (unless otherwise noted)



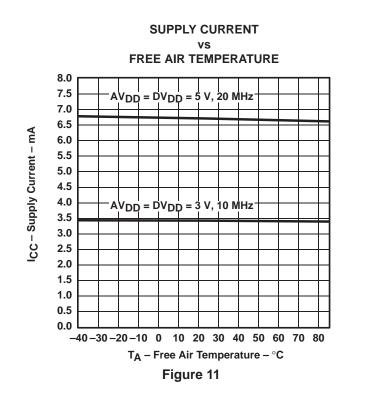
timing requirements, $AV_{DD} = DV_{DD} = 5 V$ (unless otherwise noted)

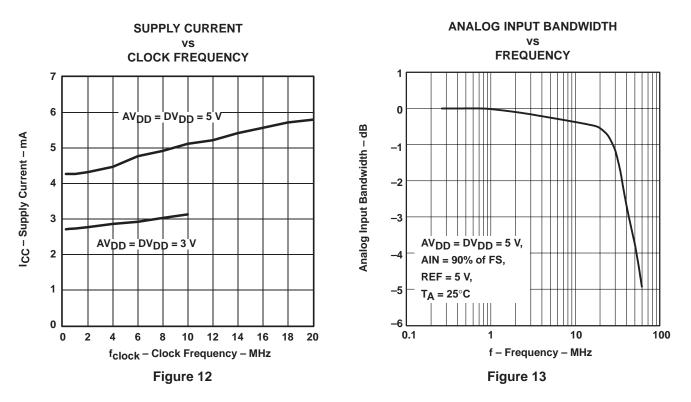
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
4	lanut de els Quele time	DV _{DD} = 4.5 V to 5.5 V	50			ns
^t c(CLK)	Input clock Cycle time	DV _{DD} = 2.7 V to 3.3 V	100			ns
^t (sample)	Reset and sampling time			6		SYSCL Cycles
t _c	Total conversion time			10		SYSCLI Cycles
^t wL(EOC)	Pulse width, end of conversion, EOC			10		SYSCLI Cycles
^t wL(INT)	Pulse width, interrupt			1		SYSCL Cycles
^t (STARTOSC)	Start-up time, internal oscillator		100			ns
td(CSH_CSTARTL)	Delay time, CS high to CSTART low			10		ns
	Enable time, data out	DV _{DD} = 5 V at 50 pF		20		ns
^t en(RDL_DAV)	Enable time, data out	DV _{DD} = 3 V at 50 pF		40		ns
	Disable time, data out	DV _{DD} = 5 V at 50 pF		5		ns
^t dis(RDH_DAV)	Disable time, data out	DV _{DD} = 3 V at 50 pF		10		ns
^t su(CSL_WRL)	Setup time, CS to WR		5			ns
^t h(WRH_CSH)	Hold time, CS to WR		5			ns
^t w(WR)	Pulse width, write		1			Clock Period
^t w(RD)	Pulse width, read		1			Clock Period
^t su(DAV_WRH)	Setup time, data valid to WR		10			ns
^t h(WRH_DAV)	Hold time, data valid to \overline{WR}		5			ns
^t su(CSL_RDL)	Setup time, CS to RD			5		ns
^t h(RDH_CSH)	Hold time, CS to RD			5		ns
^t h(WRL_EXTXLKH)	Hold time WR to clock high		5			ns
^t h(RDL_EXTCLKH)	Hold time RD to clock high		5			ns
^t h(CSTARTL_EXTCLKH)	Hold time CSTART to clock high		5			ns
^t su(WRH_EXTCLKH)	Setup time \overline{WR} high to clock high		5			ns
^t su(RDH_EXTCLKH)	Setup time RD high to clock high		5			ns
tsu(CSTARTH_EXTCLKH)	Setup time CSTART high to clock high		5			ns
^t d(EXTCLK_CSTARTL)	Delay time clock low to CSTART low		5			ns

NOTE: Specifications subject to change without notice. Data valid is denoted as DAV.



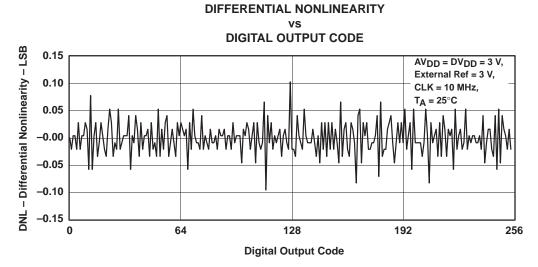








TYPICAL CHARACTERISTICS





INTEGRAL NONLINEARITY vs DIGITAL OUTPUT CODE

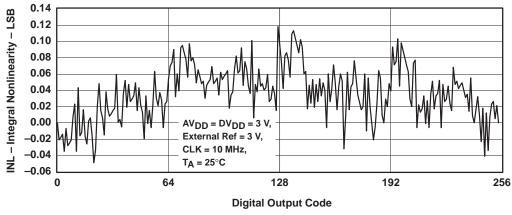
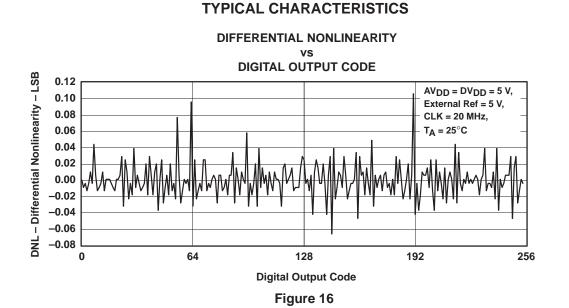
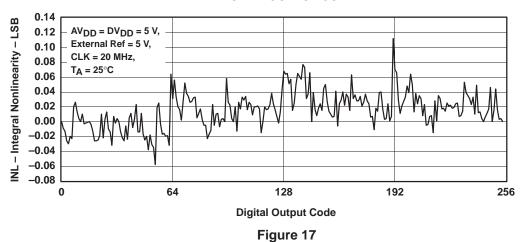


Figure 15



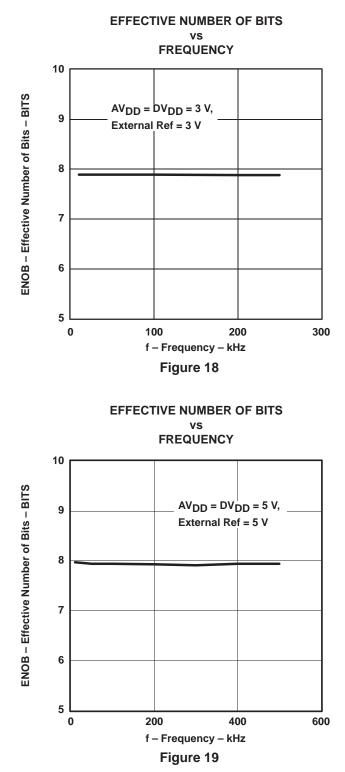


INTEGRAL NONLINEARITY vs DIGITAL OUTPUT CODE





TYPICAL CHARACTERISTICS





FAST FOURIER TRANSFORM vs FREQUENCY 20 AIN = 200 KHz 0 CLK = 10 MHz -20 Magnitude – dB $AV_{DD} = DV_{DD} = 3 V$ -40 External Ref = 3 V -60 -80 -100 -120 -140100000 200000 300000 0 f – Frequency – Hz Figure 20 FAST FOURIER TRANSFORM vs FREQUENCY 20 0 AIN = 200 KHz CLK = 20 MHz -20 Magnitude – dB $AV_{DD} = DV_{DD} = 5 V$ -40 External Ref = 5 V -60 يلا أللا -80 -100 -120 -140 0 200000 400000 600000 f - Frequency - Hz

TYPICAL CHARACTERISTICS

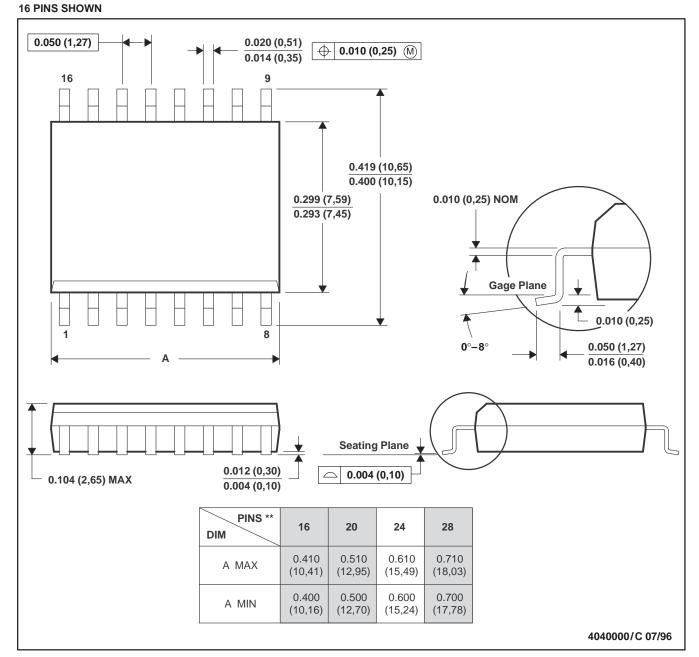
Figure 21



MECHANICAL DATA

PLASTIC SMALL-OUTLINE PACKAGE

DW (R-PDSO-G**)



NOTES: A. All linear dimensions are in inches (millimeters).

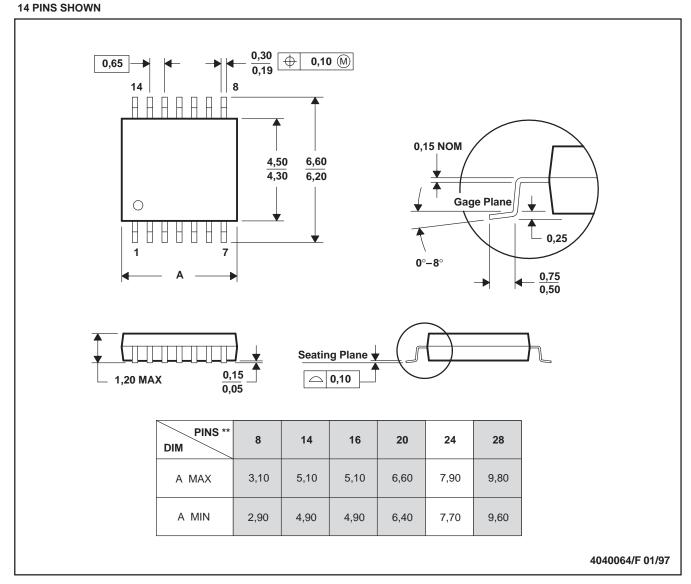
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013



MECHANICAL DATA

PLASTIC SMALL-OUTLINE PACKAGE

PW (R-PDSO-G**)



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153



19-Jun-2007

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
TLV571IDW	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV571IDWG4	ACTIVE	SOIC	DW	24	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV571IDWRG4	ACTIVE	SOIC	DW	24		TBD	Call TI	Call TI
TLV571IPW	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
TLV571IPWG4	ACTIVE	TSSOP	PW	24	60	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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